Product data sheet

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a TO263 plastic package intended for use in applications requiring very high inrush current capability, high thermal cycling performance and high junction temperature capability ($T_{i(max)} = 150$ °C).

2. Features and benefits

- High junction operating temperature capability (T_{j(max)} = 150 °C)
- · Very high current surge capability
- · Planar passivated for voltage ruggedness and reliability
- High turn-on current rise dl_T/dt = 150 A/μs
- High noise immunity dV_D/dt = 500 V/µs up to 150 °C
- · High thermal cycling performance
- · High voltage capability

3. Applications

- · High voltage capability
- · Protection circuits e.g. SMPS inrush current
- · Motor control circuits and starters
- Voltage regulation
- Solid state relays

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values			Unit
V_{DRM}	repetitive peak off-state voltage			800		V	
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{mb} \le 136 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3		40			А
I _{TSM}	non-repetitive peak on- state current half sine wave; $T_{j(init)} = 25$ °C; $t_p = 10$ ms; 450			А			
		half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms		495			Α
T _j	junction temperature			-40 to 150		0	°C
Symbol	Parameter	Conditions	Notes	Min Typ Max		Max	Unit
Static cha	aracteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$		-	-	15	mA
I _H	holding current	$V_D = 12 \text{ V}; \ T_j = 25 \text{ °C}; \underline{\text{Fig. 9}}$		-	-	60	mA
V _T	on-state voltage	ge I _T = 100 A; T _j = 25 °C; <u>Fig. 10</u>		-	-	1.65	V
Dynamic	characteristics						
dV _D /dt	V_{D}/dt rate of rise of off-state voltage $V_{DM} = 536 \text{ V}; T_{j} = 150 \text{ °C}; (V_{DM} = 67\% \text{ of } V_{DRM});$ exponential waveform; gate open circuit		-	V/µs			

SCR

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode		
2	Α	anode		A
3	G	gate		G sym037
mb	A	mounting base; connected to anode	1 3 N d	

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
TYN40B-800T	TO263	TYN40B-800TJ	Reel	800	TO263N (N)	28-Sep-2016
					TO263d (d)	17-Mar-2023

7. Marking

Table 4. Marking codes

Type number	Marking codes			
	Assembly factory: N	Assembly factory: d		
TYN40B-800T	TYN40B 800T PJNxxxx xx	TYN40B 800T PJdxxxx xx		

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
V_{DRM}	repetitive peak off-state voltage			800	V
V_{RRM}	repetitive peak reverse voltage			800	V
I _{T(AV)}	average on-state current	half sine wave; T _{mb} ≤ 136 °C;		25	Α
$I_{T(RMS)}$	RMS on-state current	half sine wave; T _{mb} ≤ 136 °C; Fig. 1; Fig. 2; Fig. 3		40	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5		450	А
		half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms		495	А
l ² t	I ² t for fusing	t _p = 10 ms; sine-wave pulse		1012	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 30 mA		150	A/µs
I _{GM}	peak gate current			5	Α
V_{GM}	peak gate voltage			5	V
V_{GRM}	peak reverse gate voltage			7	V
P_GM	peak gate power			20	W
$P_{\text{G(AV)}}$	average gate power	over any 20 ms period		1	W
T _{stg}	storage temperature			-40 to 150	°C
T _j	junction temperature			-40 to 150	°C

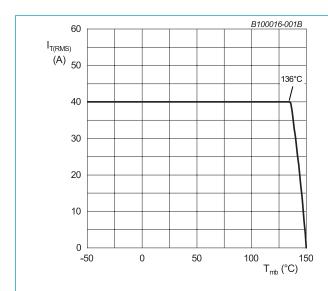
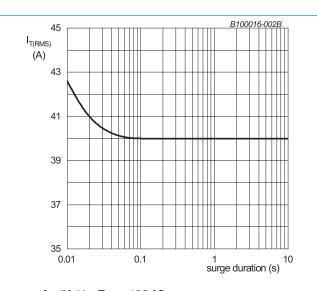
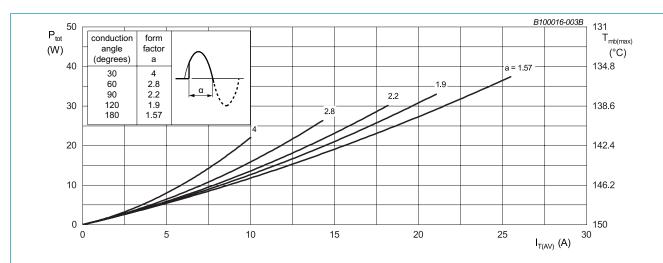


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



f = 50 Hz; T_{mb} = 136 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values

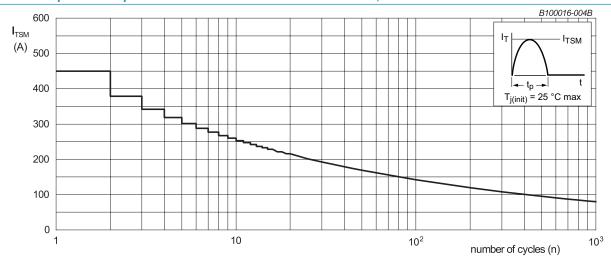
SCF



 α = conduction angle

a = form factor = $I_{T(RMS)}/I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz
 Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

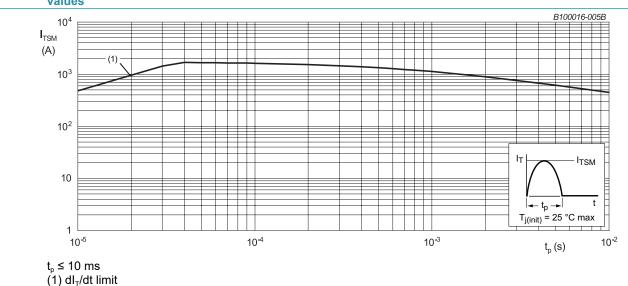


Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

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9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6		-	-	0.38	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	in free air		-	60	-	K/W

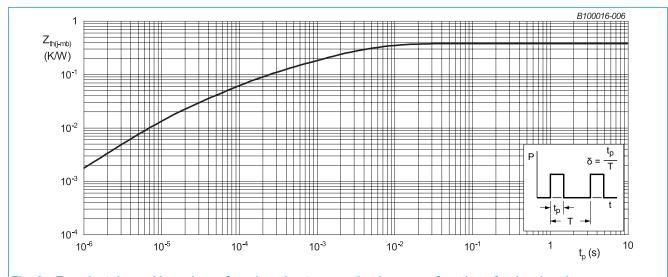


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

10. Characteristics

Table 7. Characteristics

P	0	Madaa	BA:	T	Mari	11-24
Parameter	Conditions	Notes	IVIIN	тур	wax	Unit
racteristics						
gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$		-	-	15	mA
latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 8$		-	-	80	mA
holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	60	mA
on-state voltage	I _T = 100 A; T _j = 25 °C; <u>Fig. 10</u>		-	-	1.65	V
gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C; } Fig. 11$		-	0.7	1.2	V
	V _D = 400 V; I _T = 0.1 A; T _j = 150 °C		0.25	0.5	-	V
off-state current	V _D = 800 V; T _j = 25 °C		-	-	5	μA
	V _D = 800 V; T _j = 150 °C		-	-	2	mA
reverse current	V _D = 800 V; T _j = 25 °C		-	-	5	μA
	V _D = 800 V; T _j = 150 °C		-	-	2	mA
characteristics						
rate of rise of off-state voltage	V_{DM} = 536 V; T_{j} = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		500	-	-	V/µs
gate-controlled turn-on time	$I_{TM} = 50 \text{ A}; V_D = 800 \text{ V}; I_G = 30 \text{ mA};$ $dI_G/dt = 5 \text{ A}/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$		-	2	-	μs
commutated turn-off time	$I_{TM} = 2 \text{ A}; t_p = 50 \mu\text{s}; dV/dt = 5 V/\mu\text{s}; dI/dt = 30 A/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$		-	-	25	μs
	latching current holding current on-state voltage gate trigger voltage off-state current reverse current characteristics rate of rise of off-state voltage gate-controlled turn-on time commutated turn-off	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	practeristics gate trigger current $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; \text{ Fig. 7}$ latching current $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 \text{ °C}; \text{ Fig. 8}$ holding current $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 \text{ °C}; \text{ Fig. 9}$ on-state voltage $I_T = 100 \text{ A}; T_j = 25 \text{ °C}; \text{ Fig. 10}$ gate trigger voltage $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; \text{ Fig. 11}$ $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 \text{ °C}$ off-state current $V_D = 800 \text{ V}; T_j = 25 \text{ °C}$ $V_D = 800 \text{ V}; T_j = 150 \text{ °C}$ reverse current $V_D = 800 \text{ V}; T_j = 150 \text{ °C}$ characteristics rate of rise of off-state voltage $V_{DM} = 536 \text{ V}; T_j = 150 \text{ °C}; (V_{DM} = 67\% \text{ of } V_{DRM}); \text{ exponential waveform; gate open circuit}$ gate-controlled turn-on time $I_{TM} = 50 \text{ A}; V_D = 800 \text{ V}; I_G = 30 \text{ mA};$ $dI_G/dt = 5 \text{ A}/\mu \text{s}; T_j = 25 \text{ °C}$ commutated turn-off $I_{TM} = 2 \text{ A}; t_p = 50 \mu \text{s}; \text{ dV/dt} = 5 \text{ V/} \mu \text{s}; \text{ dI/dt}$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

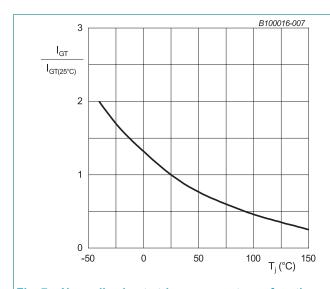


Fig. 7. Normalized gate trigger current as a function of junction temperature

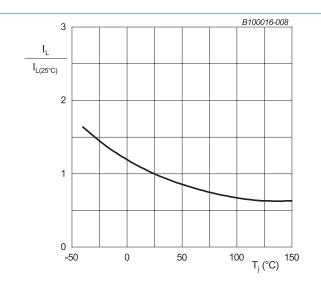


Fig. 8. Normalized latching current as a function of junction temperature

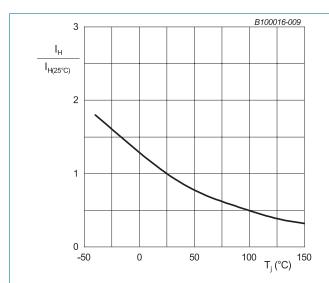
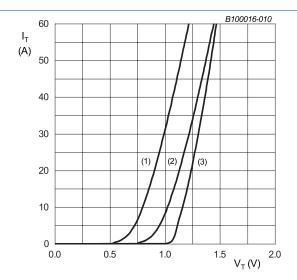


Fig. 9. Normalized holding current as a function of junction temperature



 V_o = 0.992 V; R_s = 0.0076 Ω (1) T_j = 150 °C; typical values (2) T_j = 150 °C; maximum values (3) T_j = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

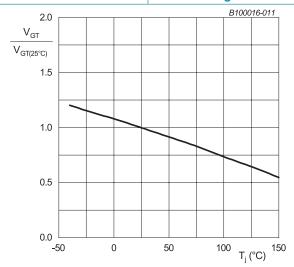
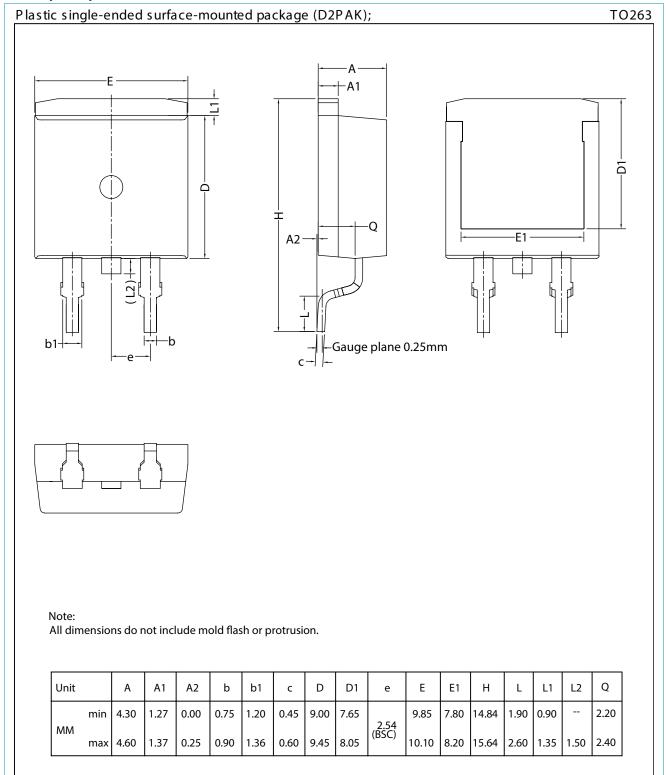


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

11. Package outline Assembly factory: N Plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped) TO263 A1H 7 A2-10.60-7.50 5.08-Recommended Footprint Q Unit Α1 Α2 b b1 \mathbb{D} D1 D2 Ε E1 Н L1 L2 C 7.80 14.80 2.10 2.20 4.10 1.22 0.00 0.60 1.05 0.34 1,20 6.60 9.70 min 2.54 (BSC) 0.25 (BSC.) 2.79 0.25 | 0.90 | 1.45 | 0.64 | 11.00 | 1.60 4.70 | 1.40 10.30 15.80 2.90 1.75 max

Assembly factory: d



12. Legal information

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Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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